

10/569209

1AP20 Rec'd PCT/PTO 23 FEB 2006
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Takashi YAMADA et al.

Application No.: New U.S. National Stage of
PCT/JP2004/012302

Filed: February 23, 2006

Docket No.: 127154

For: WARPAGE ANGLE MEASUREMENT APPARATUS AND WARPAGE ANGLE
MEASUREMENT METHOD FOR OPTICAL RECORDING MEDIUM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

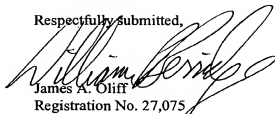
- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. Relevance of one or more non-English language reference is discussed in the present specification. See Reference 1.
- ☒ 3. One or more reference cited herein was cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information. See References 2-13.
- ☒ 4. An English language Abstract of one or more non-English language reference is attached hereto. See References 1-12.

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5. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office (<http://www.jpo.go.jp>), and is attached, but has not been reviewed for accuracy. See References 1-9 & 11.

Respectfully submitted,



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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 127154		<div style="font-size: 2em; font-weight: bold; margin: 0;">10/569209</div> <div style="font-size: 0.8em; margin: 0;">APPLICATION NO. (New & Substantive) Serial of PCT/JP2004/012302</div>	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Takashi YAMADA et al.			
				FILING DATE February 23, 2006			

U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Name		

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
/KC/	1	JP A 2003-085836	03/20/2003	JAPAN	X	X
/KC/	2	JP A 2003-091883	03/28/2003	JAPAN	X	X
/KC/	3	JP A 2003-059097	02/28/2003	JAPAN	X	X
/KC/	4	JP A 2003-132596	05/09/2003	JAPAN	X	X
/KC/	5	JP A 08-233543	09/13/1996	JAPAN	X	X
/KC/	6	JP A 2001-257461	09/21/2001	JAPAN	X	X
/KC/	7	JP A 2001-041718	02/16/2001	JAPAN	X	X
/KC/	8	JP A 2003-132591	05/09/2003	JAPAN	X	X
/KC/	9	JP A 10-078310	03/24/1998	JAPAN	X	X
/KC/	10	JP A 64-1904	01/06/1989	JAPAN	X	
/KC/	11	JP A 2002-313050	10/25/2002	JAPAN	X	X
/KC/	12	JP A 04-276354	10/01/1992	JAPAN	X	
/KC/	13	JP U 05-90656	12/10/1993	JAPAN		

OTHER DOCUMENTS		
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER /Kim Kwok Chu/ (06/20/2008)	DATE CONSIDERED 06/20/2008
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Examiner:	Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.
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